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---

1 **A test methodology for wafer scale system**
*Landis, D.L.;*
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction
on , Volume: 11 , Issue: 1 , Jan 1992
Pages:76 - 82

[Abstract]    [PDF Full-Text (644 KB)]    **IEEE JNL**

---

2 **A hierarchical test methodology for systems on chip**
*Jin-Fu Li; Hsin-Jung Huang; Jeng-Bin Chen; Chih-Pin Su; Cheng-Wen Wu; Ch
Cheng; Shao-I Chen; Chi-Yi Hwang; Hsiao-Ping Lin;*
Micro, IEEE , Volume: 22 , Issue: 5 , Sept.-Oct. 2002
Pages:69 - 81

[Abstract]    [PDF Full-Text (396 KB)]    **IEEE JNL**

---

3 **A parallel built-in self-diagnostic method for embedded memory arr**
*Der-Cheng Huang; Wen-Ben Jone;*
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction
on , Volume: 21 , Issue: 4 , April 2002
Pages:449 - 465

[Abstract]    [PDF Full-Text (475 KB)]    **IEEE JNL**

---

4 **Oscillation-test methodology for low-cost testing of active analog fi**
*Arabi, K.; Kaminska, B.;*
Instrumentation and Measurement, IEEE Transactions on , Volume: 48 , Issu
4 , Aug. 1999
Pages:798 - 806

[Abstract]    [PDF Full-Text (180 KB)]    IEEE JNL

___

5 **Full operation of a three-node pipeline-ring switching chip for a superconducting network system**
*Yorozu, S.; Hashimoto, Y.; Numata, H.; Koike, M.; Tanaka, M.; Tahara, S.;*
Applied Superconductivity, IEEE Transactions on , Volume: 9 , Issue: 2 , June

Pages:3590 - 3593

[Abstract]    [PDF Full-Text (576 KB)]    IEEE JNL

___

6 **Design of Boeing 777 electric system**
*Andrade, L.; Tenning, C.;*
Aerospace and Electronic Systems Magazine, IEEE , Volume: 7 , Issue: 7 , Ju
1992
Pages:4 - 11

[Abstract]    [PDF Full-Text (652 KB)]    IEEE JNL

___

7 **An implantable CMOS circuit interface for multiplexed microelectroc recording arrays**
*Ji, J.; Wise, K.D.;*
Solid-State Circuits, IEEE Journal of , Volume: 27 , Issue: 3 , March 1992
Pages:433 - 443

[Abstract]    [PDF Full-Text (904 KB)]    IEEE JNL

___

8 **Designing in power-down test circuits**
*Levy, P.S.;*
Design & Test of Computers, IEEE , Volume: 8 , Issue: 3 , Sept. 1991
Pages:31 - 35

[Abstract]    [PDF Full-Text (288 KB)]    IEEE JNL

___

9 **Serial interfacing for embedded-memory testing**
*Nadeau-Dostie, B.; Silburt, A.; Agarwal, V.K.;*
Design & Test of Computers, IEEE , Volume: 7 , Issue: 2 , April 1990
Pages:52 - 63

[Abstract]    [PDF Full-Text (784 KB)]    IEEE JNL

___

10 **A 16-Mbit/s adapter chip for the IBM token-ring local area networl**
*Blair, J.D.; Correale, A., Jr.; Cranford, H.C.; Dombrowski, D.A.; Erdelyi, C.K.; Hoffman, C.R.; Lamphere, J.L.; Lang, K.W.; Lee, J.K.; Mullen, J.M.; Norman, Oakland, S.F.;*
Solid-State Circuits, IEEE Journal of , Volume: 24 , Issue: 6 , Dec. 1989
Pages:1647 - 1655

[Abstract]    [PDF Full-Text (840 KB)]    IEEE JNL

___

11 **Off-chip $I_{ddq}$ monitor with standard test interface**
*Pedros, J.; Rubio, A.;*
Electronics Letters , Volume: 31 , Issue: 14 , 6 July 1995

Pages:1139 - 1140

[Abstract]    [PDF Full-Text (192 KB)]    IEE JNL

---

12 **Robust/low cost SSPCs are finally available**
*Friedman, S.;*
Digital Avionics Systems Conference, 1997. 16th DASC., AIAA/IEEE , Volume
2 , 26-30 Oct. 1997
Pages:7.3 - 31-7.3-36 vol.2

[Abstract]    [PDF Full-Text (468 KB)]    IEEE CNF

---

13 **Boundary scan access of built-in self-test for field programmable g arrays**
*Gibson, G.; Gray, L.; Stroud, C.;*
ASIC Conference and Exhibit, 1997. Proceedings., Tenth Annual IEEE
International , 7-10 Sept. 1997
Pages:57 - 61

[Abstract]    [PDF Full-Text (512 KB)]    IEEE CNF

---

14 **A smart sensing microsystem with a capacitive sensor interface**
*Yazdi, N.; Mason, A.; Najafi, K.; Wise, K.D.;*
Circuits and Systems, 1996. ISCAS '96., 'Connecting the World'., 1996 IEEE
International Symposium on , Volume: 4 , 12-15 May 1996
Pages:336 - 339 vol.4

[Abstract]    [PDF Full-Text (364 KB)]    IEEE CNF

---

15 **Development of on-line diagnosis system using intelligent devices semiconductor equipment**
*Noguchi, T.; Aizono, T.; Kawano, K.; Ohashi, M.; Kogure, M.;*
SICE 2002. Proceedings of the 41st SICE Annual Conference , Volume: 5 , 5-
2002
Pages:3246 - 3250 vol.5

[Abstract]    [PDF Full-Text (353 KB)]    IEEE CNF

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